

**Search Notes**

Application/Control No.

10/563,030

Examiner

Muhammad Akbar

Applicant(s)/Patent under  
Reexamination

STEFFEN ET AL.

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Words searches in EAST using class 455/423,425,67.11 (attached search history)	8/27/2007	MA
Words searches by using keywords wireless device under test for measuring high frequency	8/27/2007	MA
IEEE/WIPO/EPO documents searches by using keywords wireless device under test for measuring high frequency	8/31/2007	MA